Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/662,554	PHAM, HIEP THE
Examiner	Art Unit
 Hai L. Nguyen	2816

SEARCHED					
Class	Subclass	Date	Examiner		
327	156,157, 162,163, 146-148	4/27/2005	HLN		
	3,5,7,12				
	40,42-44				
	47-49				
\bigvee	71-77				
331	DIG.2				
	1A,1R				
375	373-376	1	V		

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
Search	Search Above		HLN			
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SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
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